

Robust Characterization of Quantum Processes

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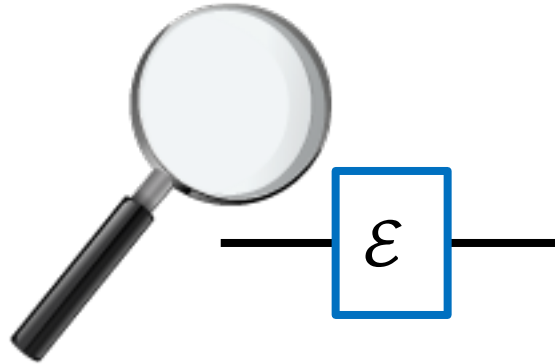
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Raytheon BBN Technologies

Why don't we have a working quantum computer?

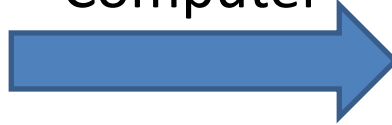
Too Many Errors

Can Improve Operations with Better Characterization of Errors

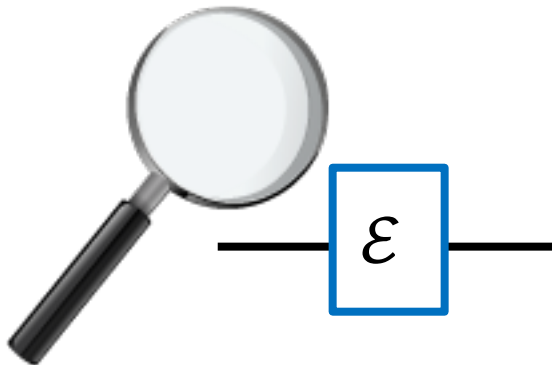


“Depolarizing error”

Improvement to
Computer



Cooling



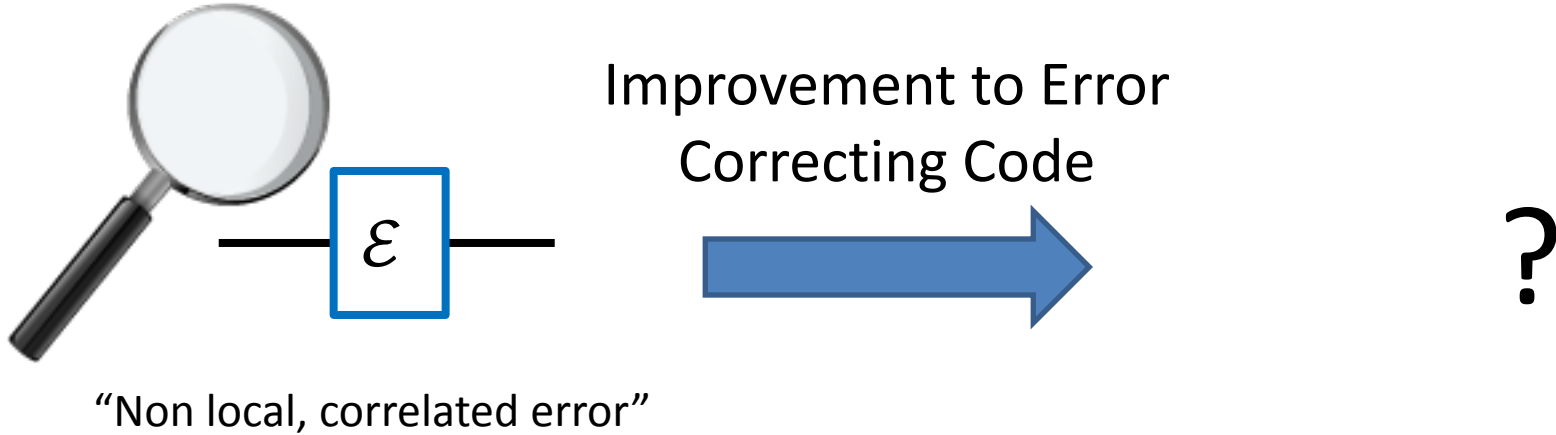
“Extra rotation around z-axis”

Improvement to
Computer

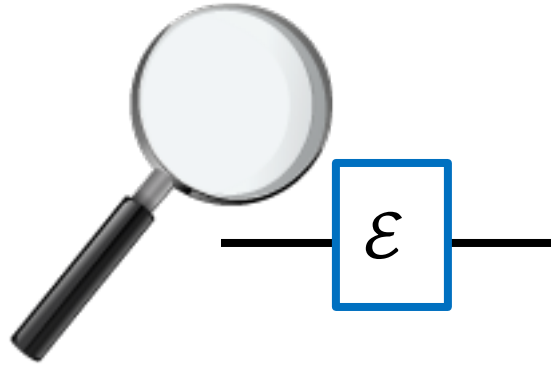


Magnetic
Shielding

Can Improve Error Correcting Codes with Better Characterization of Errors



Standard Techniques Have Problems



Need nearly perfect state preparation, measurement and other operations. Otherwise systematic errors give inaccurate or even invalid results.

Not “robust”

Robust Techniques

- Gate Set Tomography Procedures [Stark '13, Blume-Kohout et al. '13, Merkel et al. '12]
 - Characterizes many processes at once
- Randomized Benchmarking (RB) [Emerson et al. '05, Knill et al. '08, Magesan et al. '11, '12]
 - Can only characterize ~~1~~ parameter of ~~1~~ type of process.
almost all any
 - Can efficiently test performance of a universal gate set.

Outline

- **Background:**

- Issues with standard process characterization
- Randomized benchmarking framework, challenges of current implementation

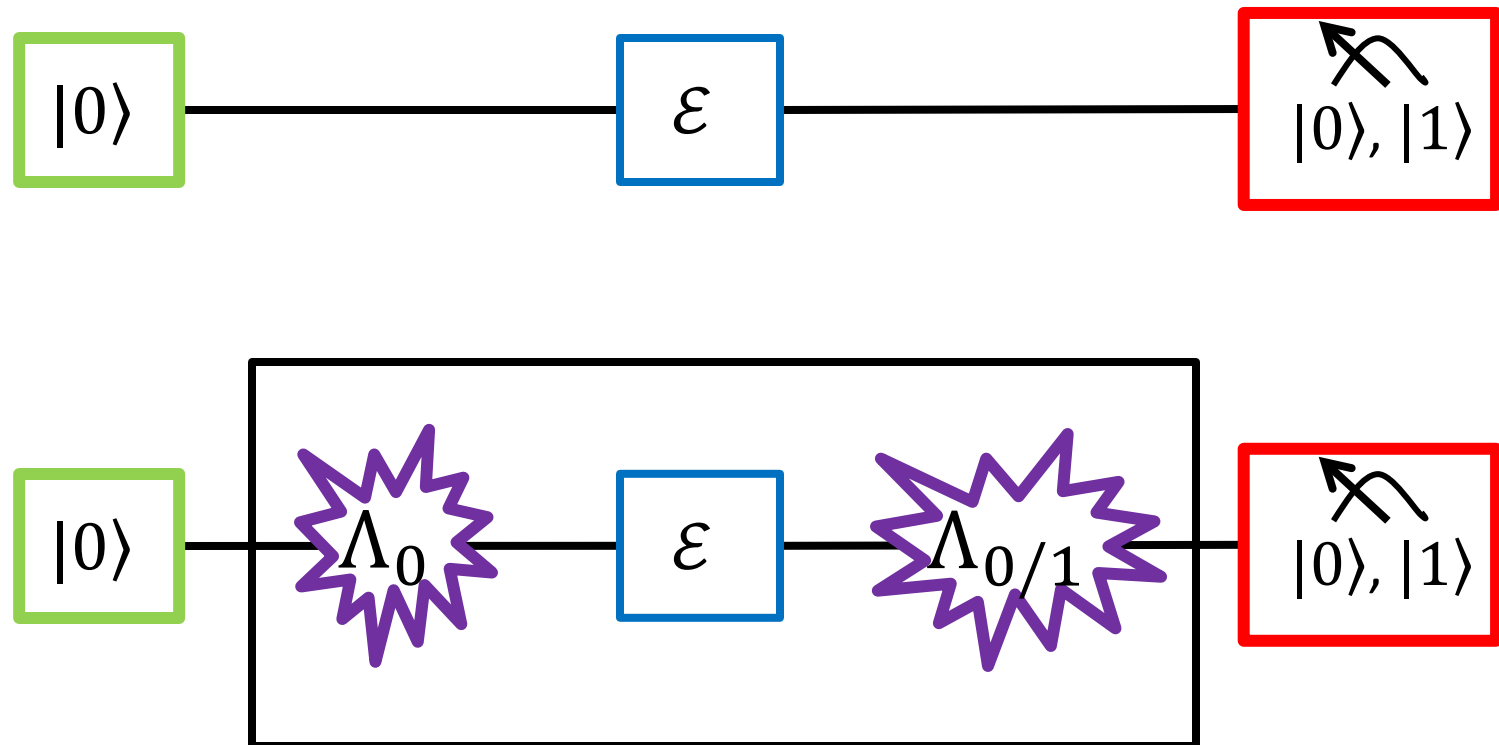
- **Our Results:**

- Robust characterization of unital part of any process
- Efficient bound on average fidelity of universal gate set.

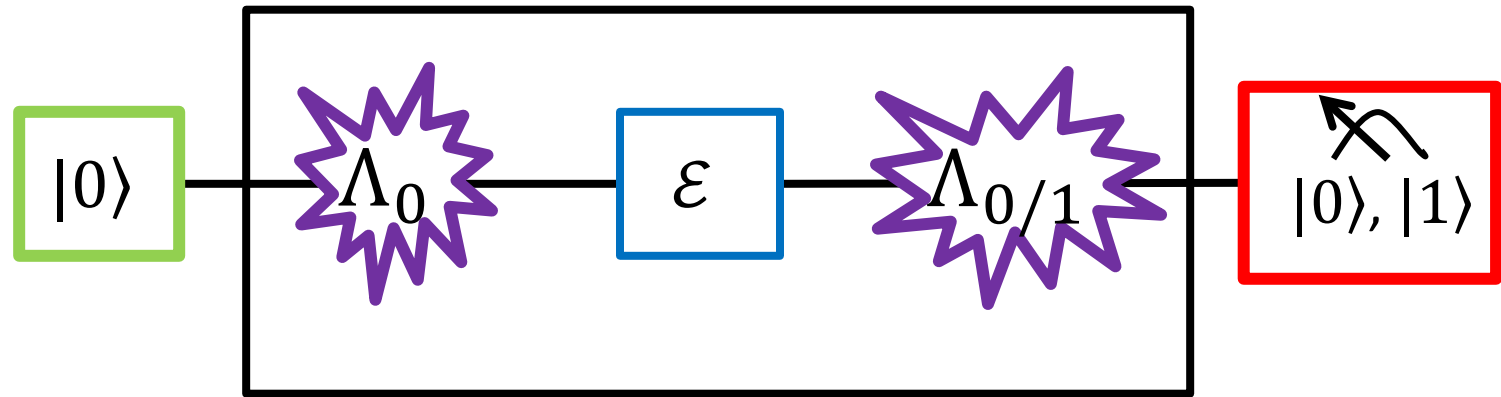
Quantum Process (Map)

- Completely positive trace preserving (CPTP) map = any process that takes valid quantum states to valid quantum states.
- E.g. unitary, depolarizing process, dephasing process, amplitude damping process
- n qubits, $O(16^n)$ free parameters

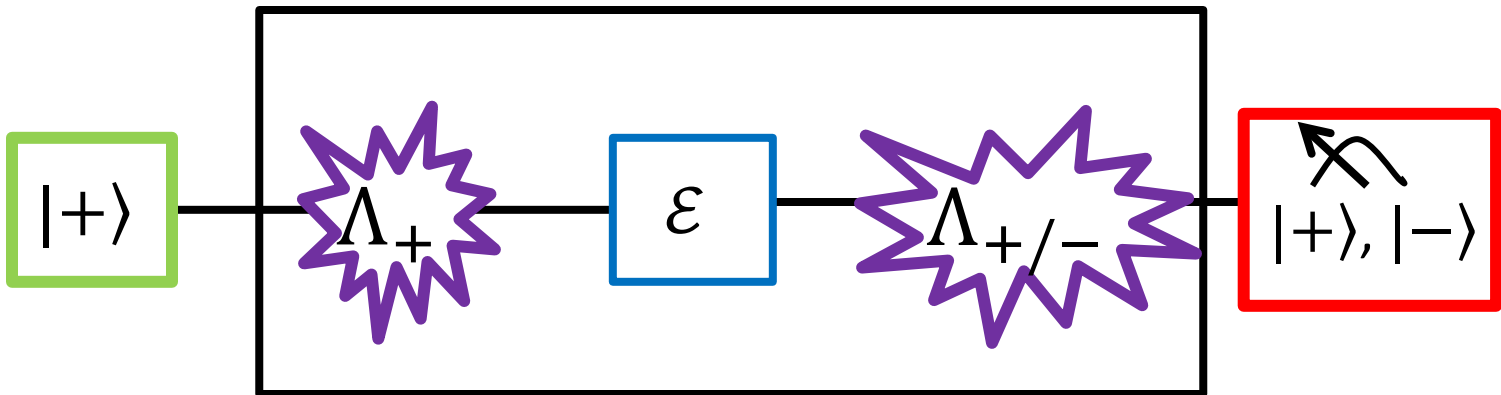
Problem with Standard Process Tomography



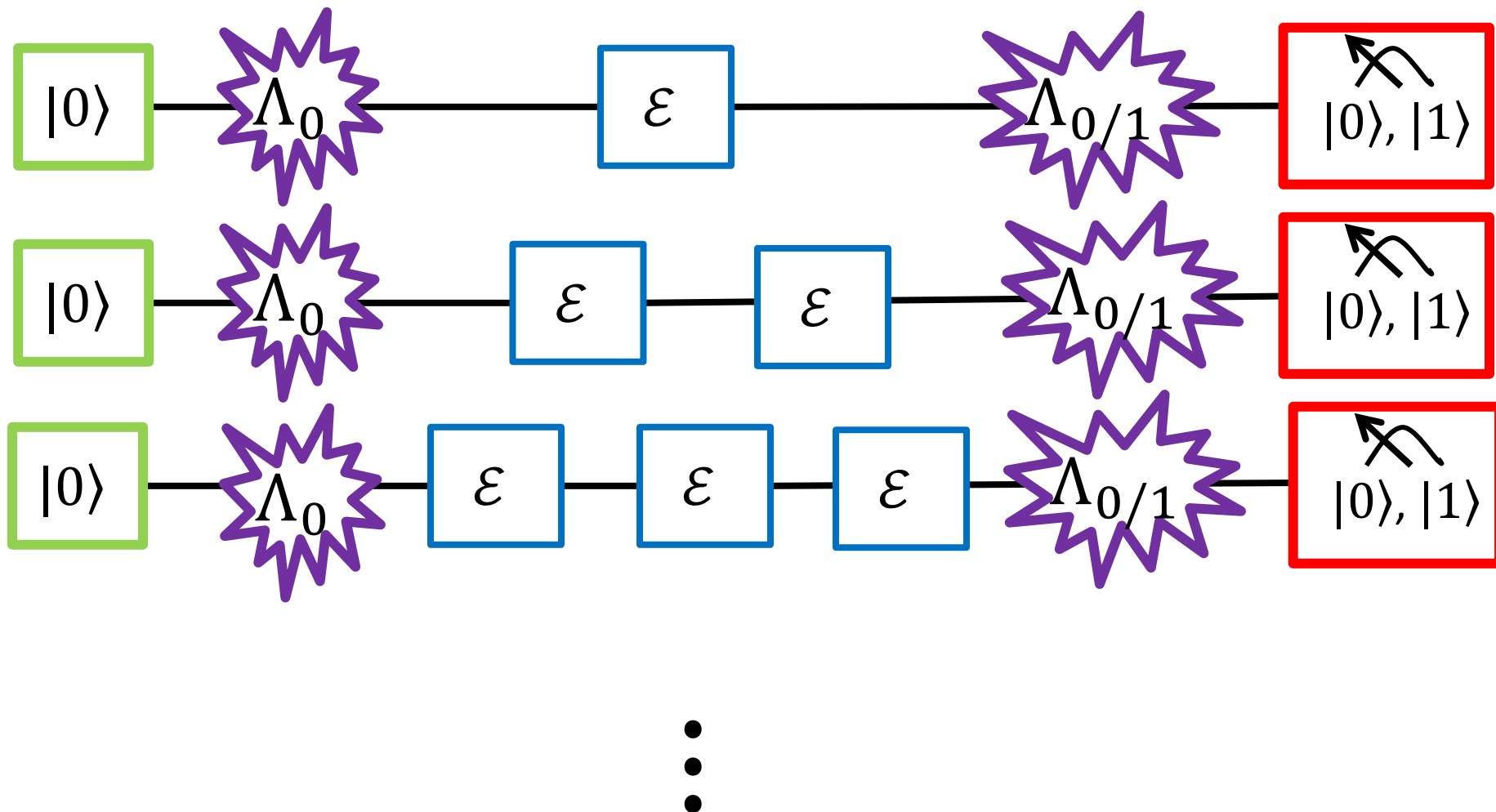
Problem with Standard Process Tomography



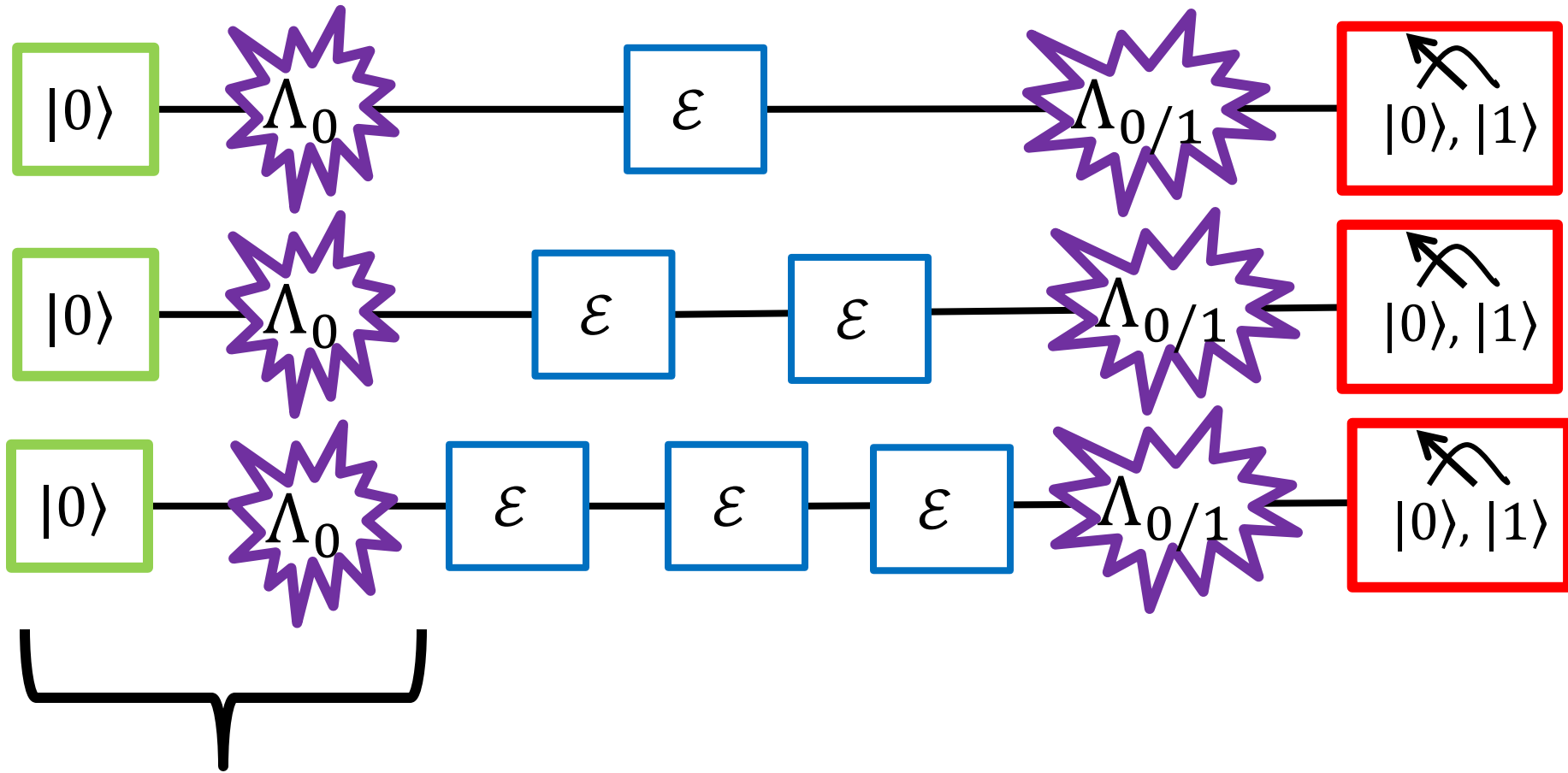
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Repeated Application

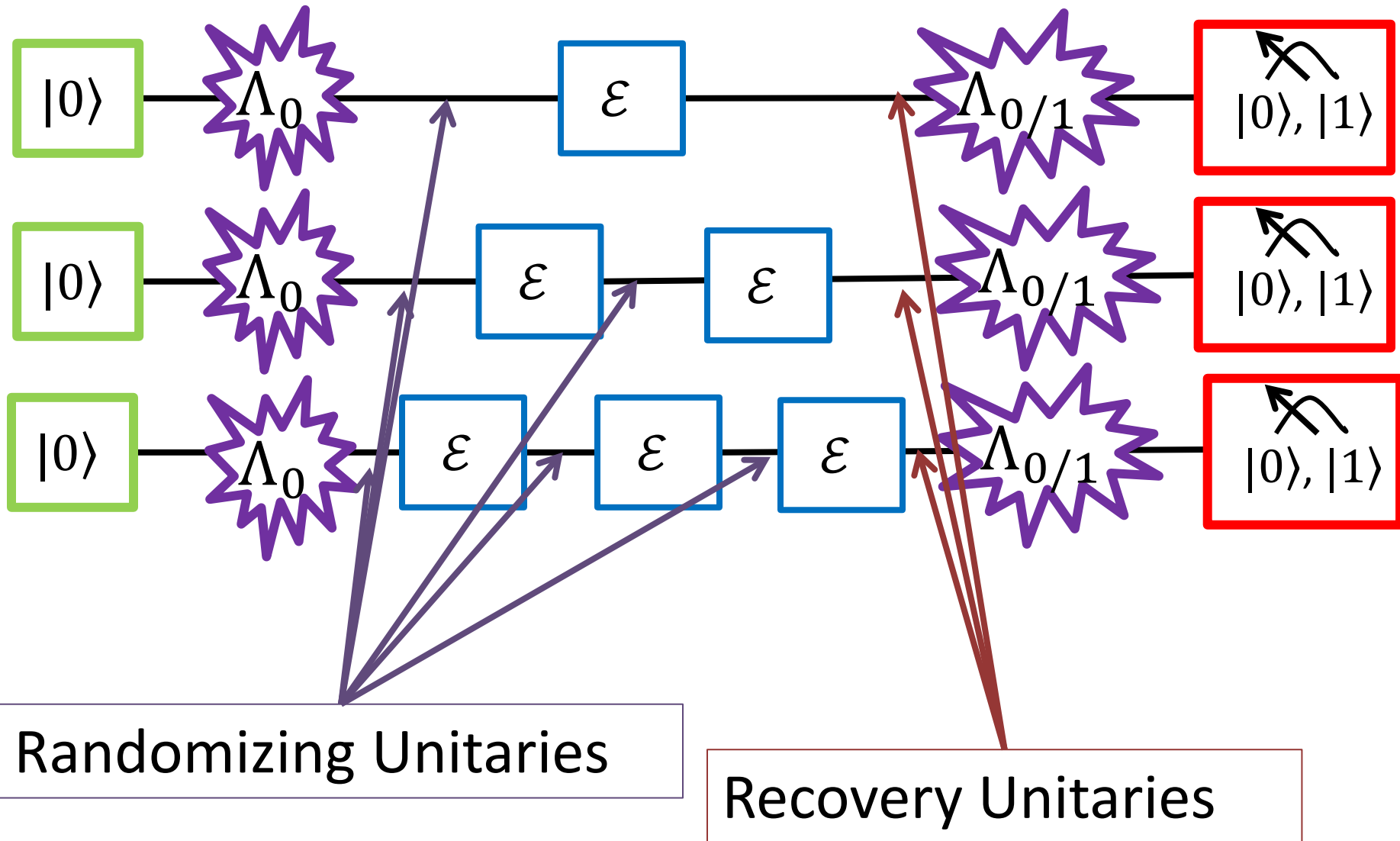


Repeated Application



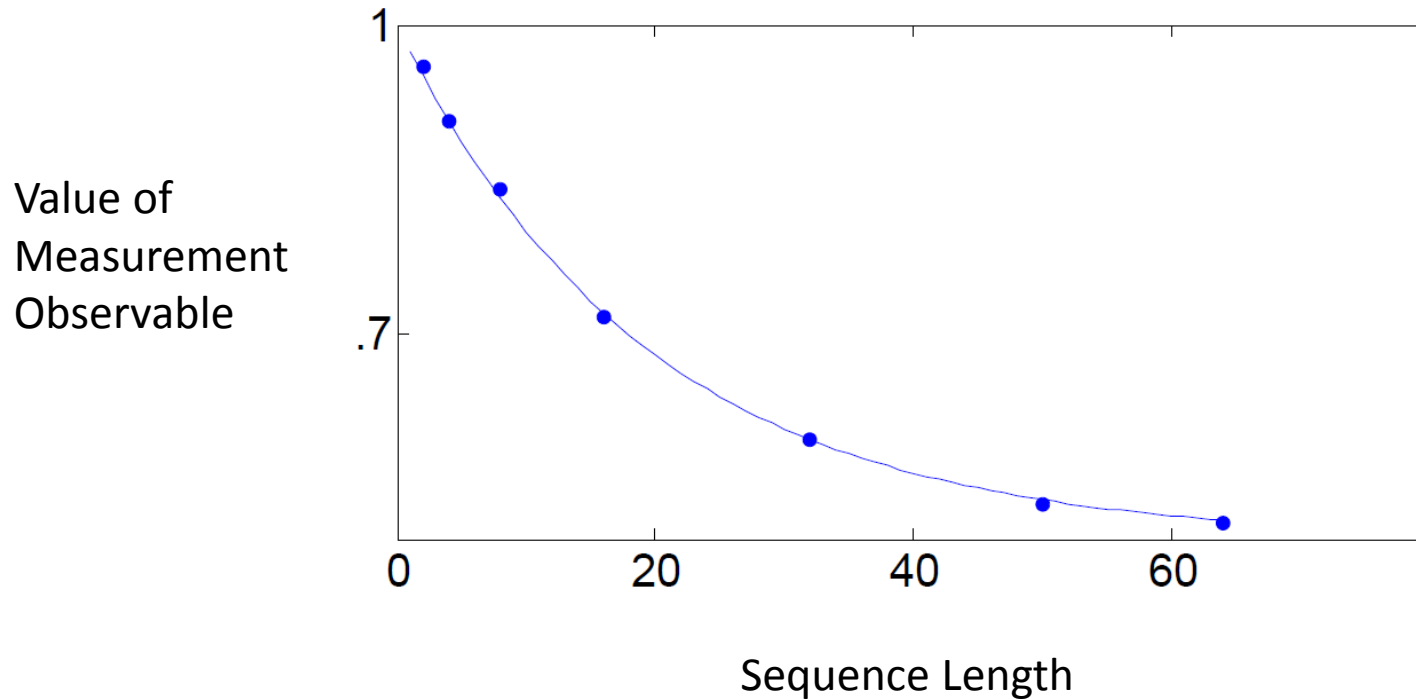
If eigenstate of \mathcal{E} , will only see how \mathcal{E} acts on *this* state

Randomized Benchmarking



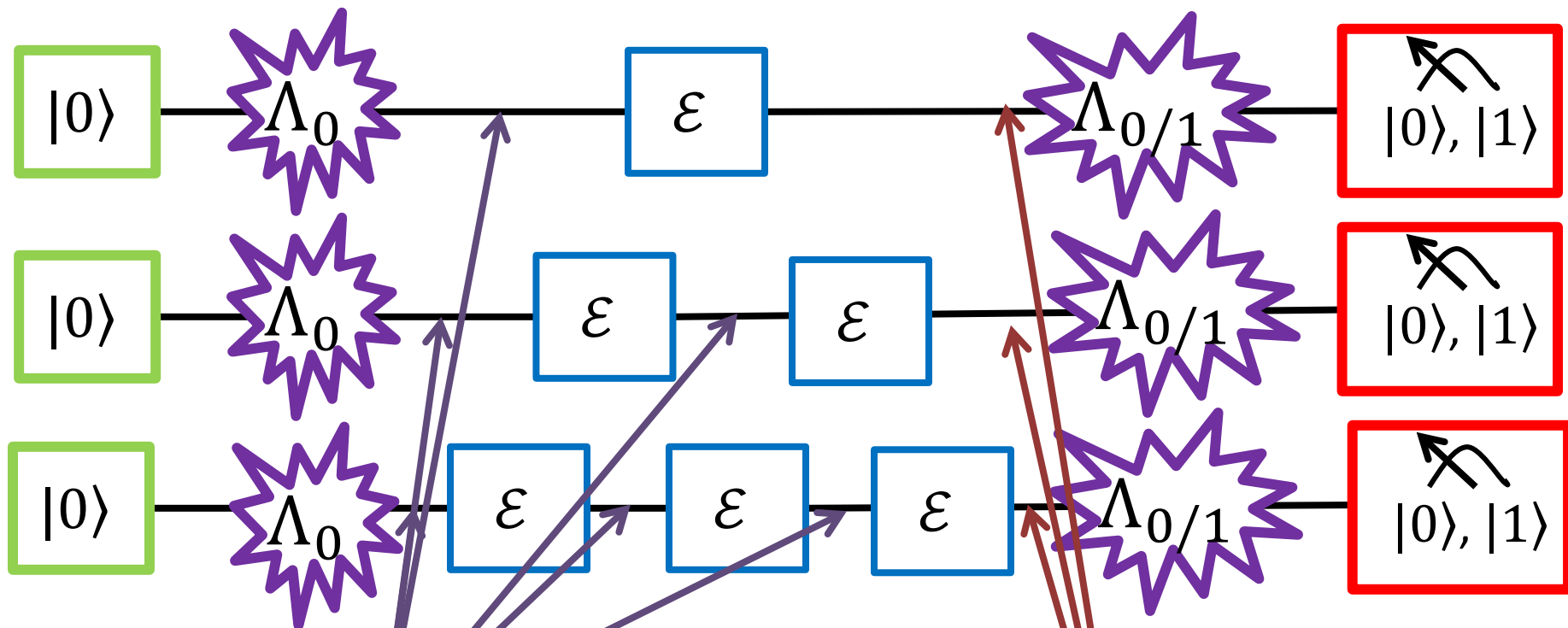
Randomized Benchmarking

Simulated Randomized Benchmarking Experiment



Decay constant depends on one parameter of \mathcal{E}

Randomized Benchmarking



Randomizing Unitaries
Have Errors!

Recovery Unitaries

Two Issues with RB

1. How can we extract more than just 1 parameter?
2. How can we deal with errors on the randomizing operations?

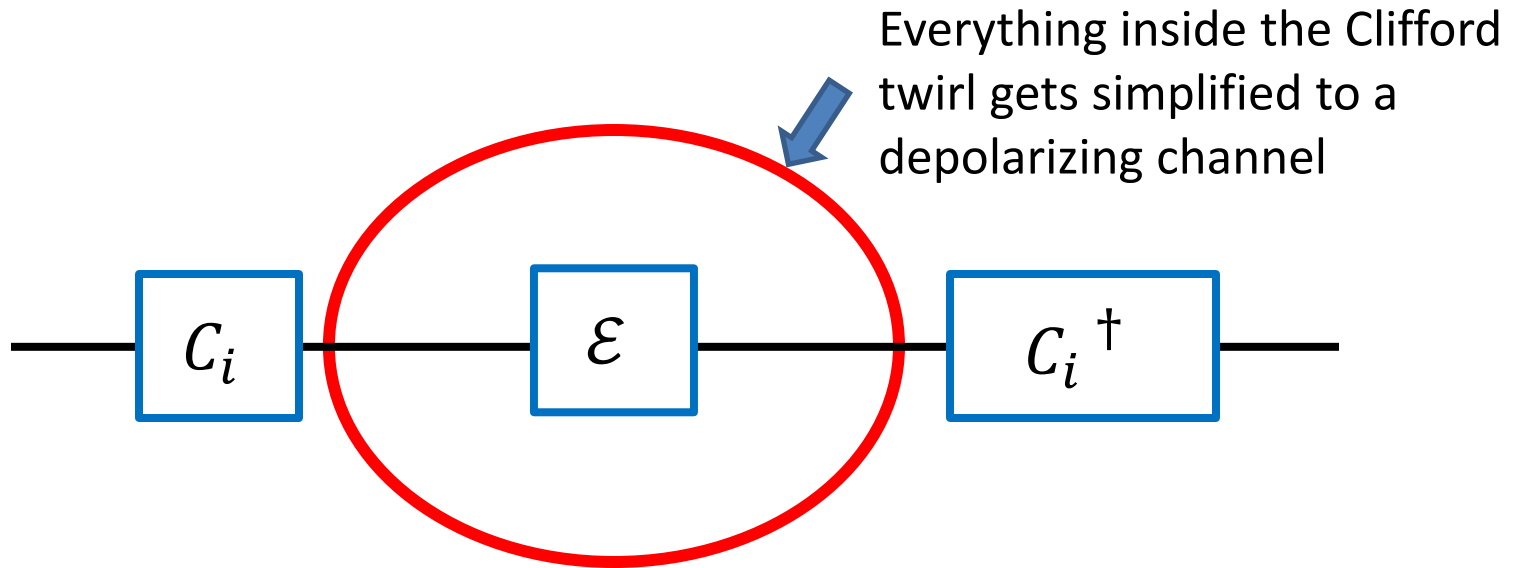
Randomizing Operation: Clifford Twirl

$$\frac{1}{|\mathcal{C}_i|} \sum_{C_i \text{ in Cliffords}} C_i^\dagger \circ \mathcal{E} \circ C_i (\rho) = (1 - q)\rho + q \frac{\mathbb{I}}{d}$$

Result is depolarizing channel (very simple process)
that depends on only one parameter of \mathcal{E} :
Average fidelity of \mathcal{E} to the identity

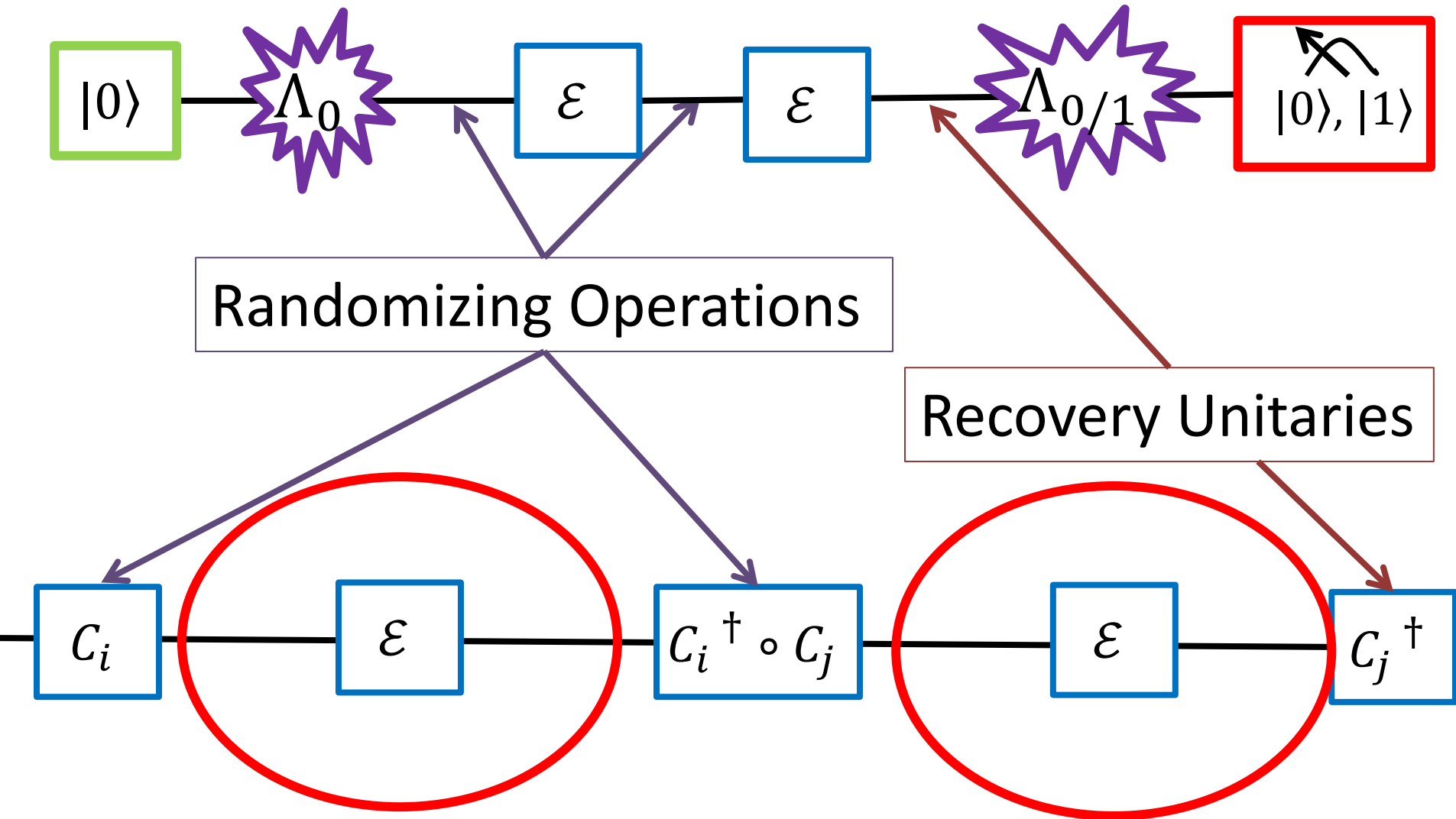
$$\text{Average fidelity of } \mathcal{E} = \int d|\psi\rangle \langle\psi| \mathcal{E}(|\psi\rangle\langle\psi|) |\psi\rangle$$

Randomizing Operation: Clifford Twirl



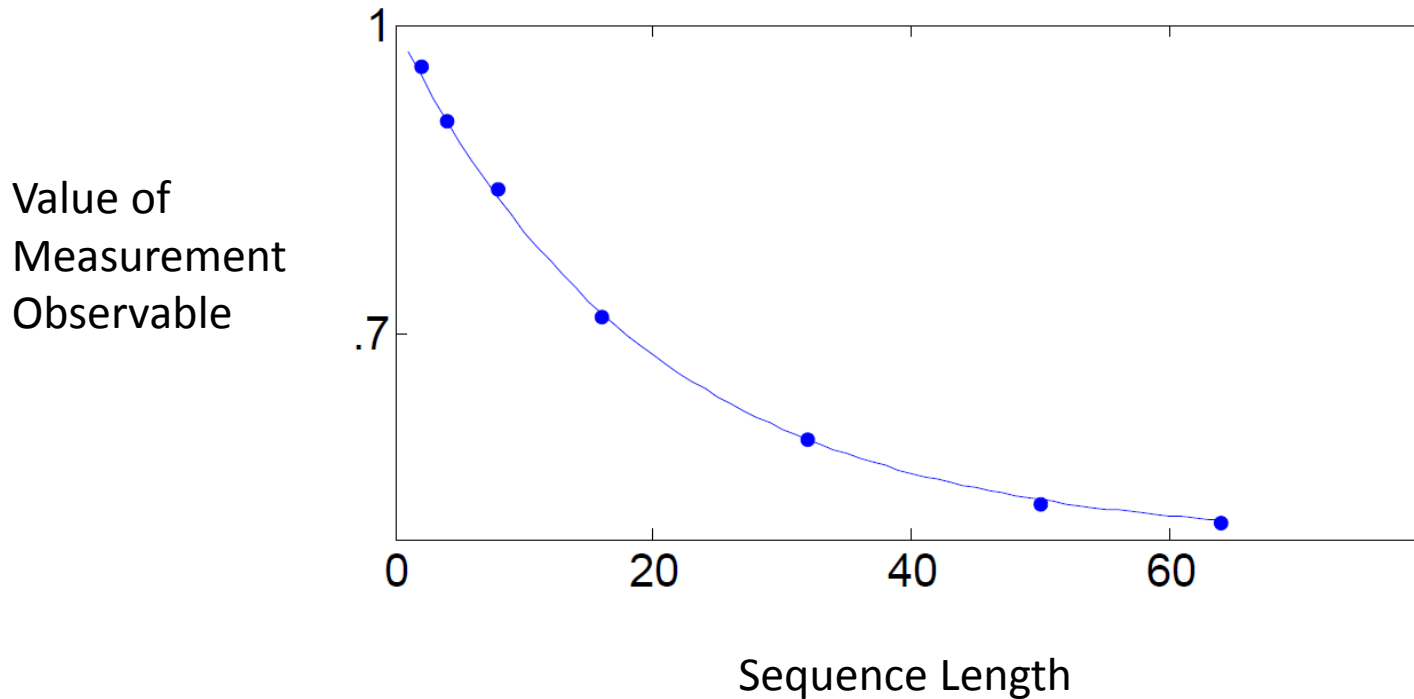
To implement (approximately), repeat many times, each time randomly choosing C_i , and average results

Randomizing Operation: Clifford Twirl



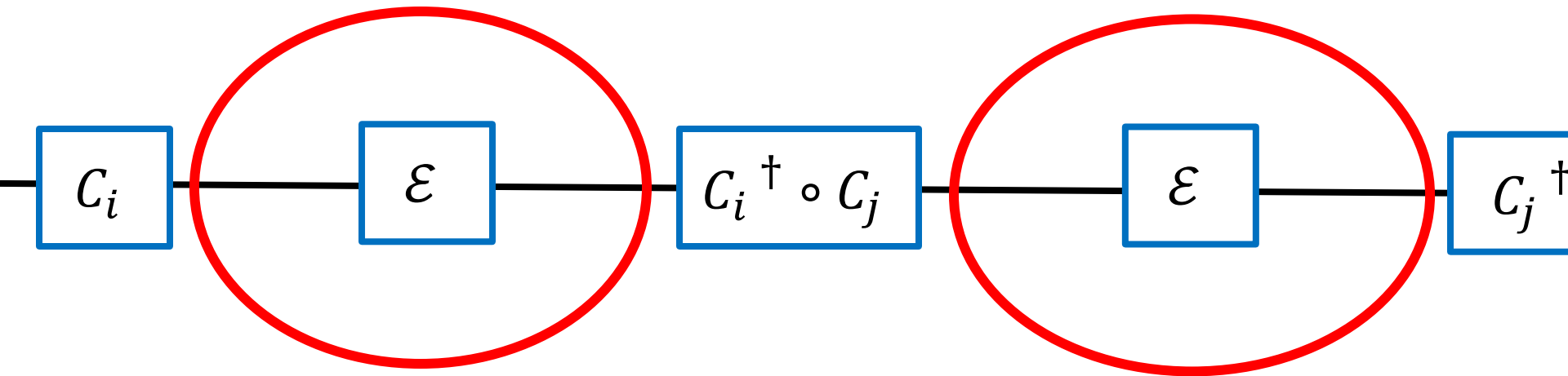
Randomizing Operations

Simulated Randomized Benchmarking Experiment



Decay constant depends on 1 parameter of \mathcal{E} :
Average fidelity of \mathcal{E} to the identity.

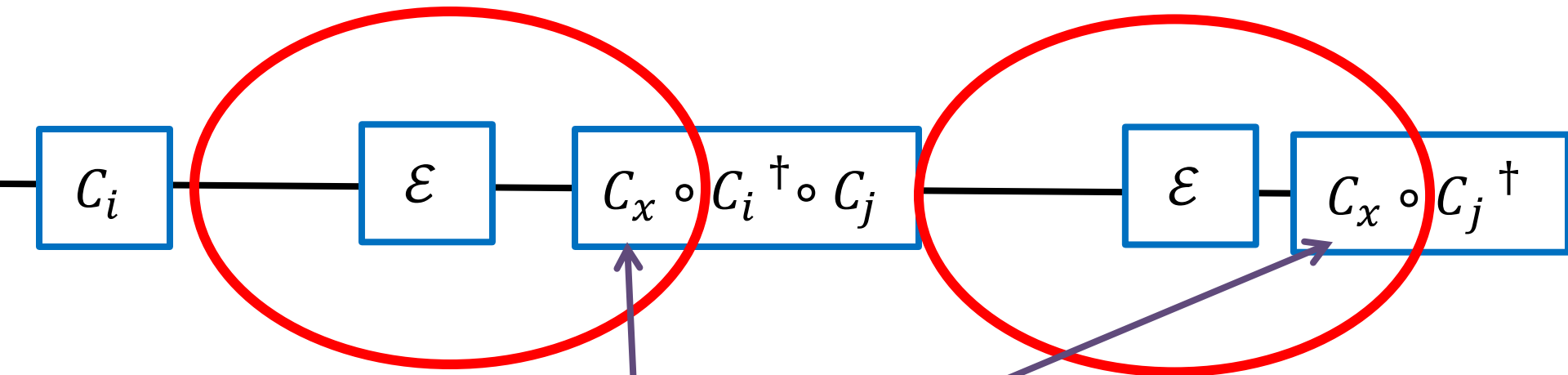
1. Extracting More Information



Twirl simplifies too much!

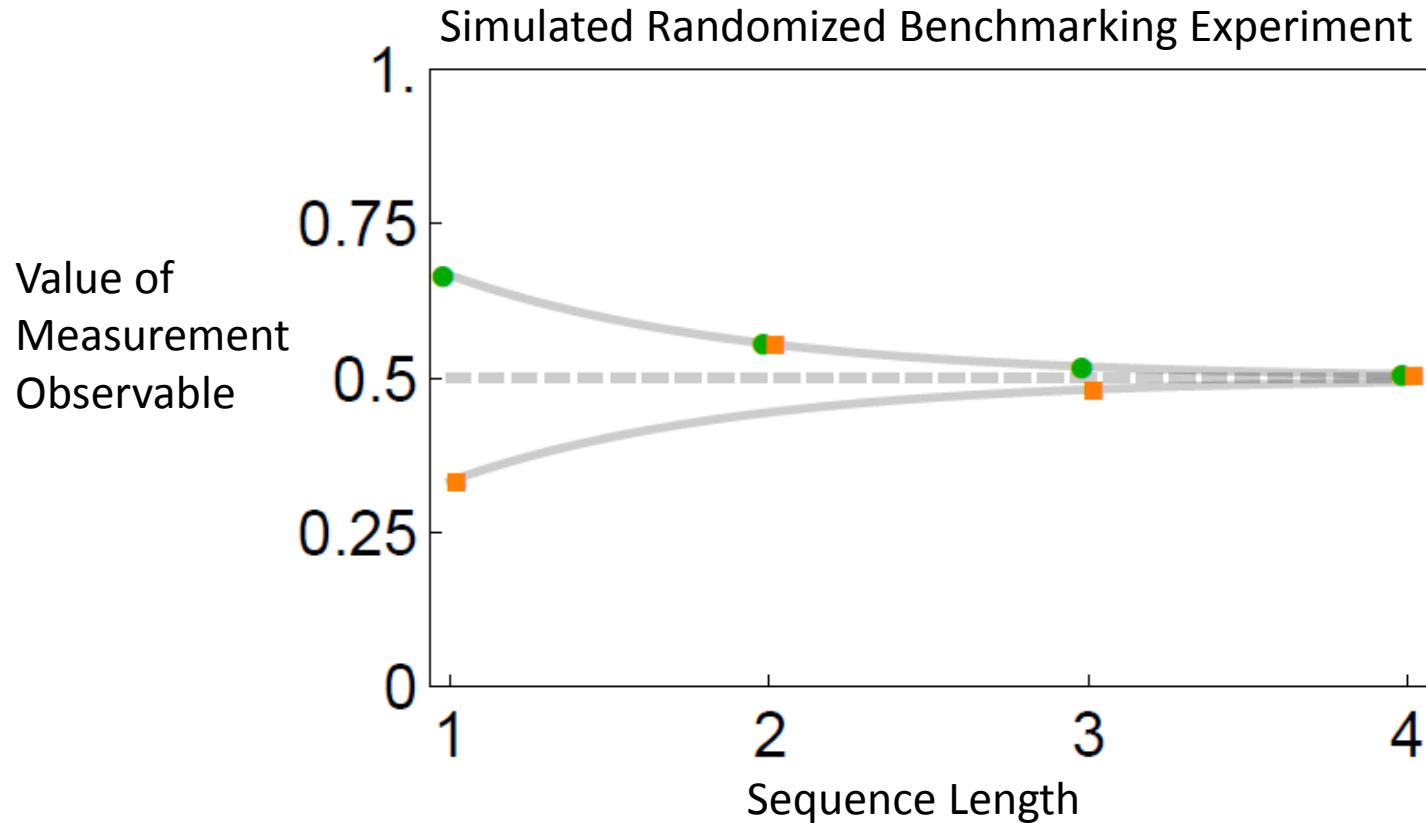
- no twirl
- stick additional information inside twirl

1. Extracting More Information



C_x is fixed – not random. The same C_x is applied in each twirl.

1. Extracting More Information



Decay constant depends on 1 parameter of \mathcal{E} :

Average Fidelity of \mathcal{E} to C_x^\dagger (can have fast decays)

1. Extracting More Information

CPTP map: $16^n - 4^n$ parameters for n -qubit map

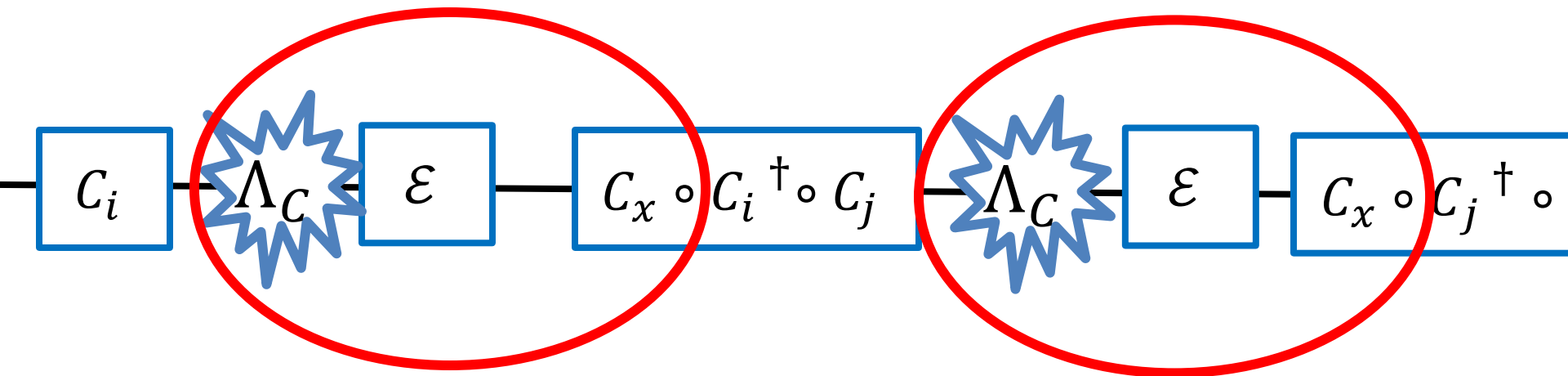
To compose two maps, just multiply matrices!

$$4^n \begin{bmatrix} 1 & 0 & \dots & 0 \\ \hline & \text{hatched} & & \end{bmatrix}$$

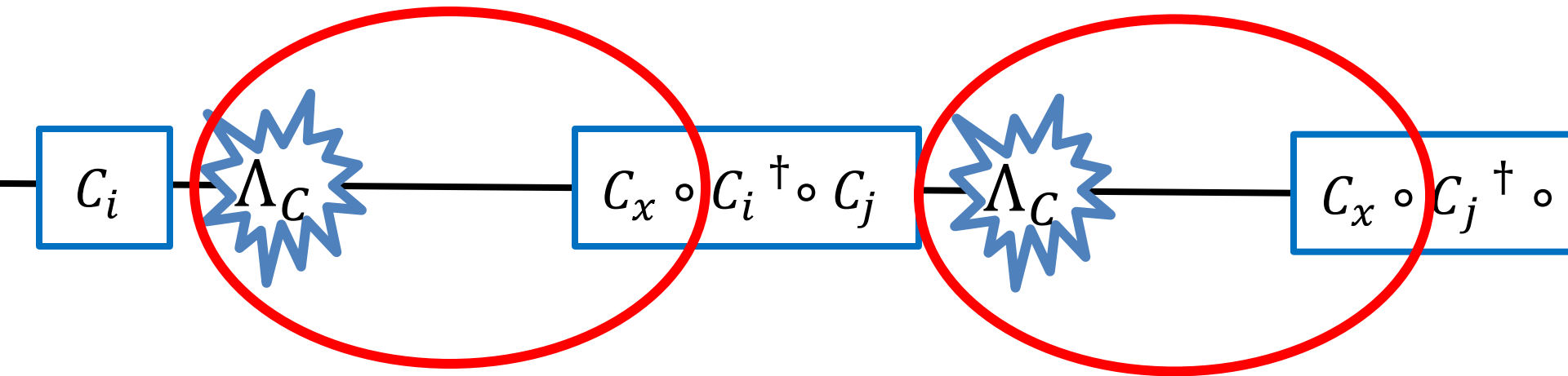
The diagram shows a square matrix of size $4^n \times 4^n$. The top row is highlighted with a thick red line and contains the elements 1, 0, ..., 0. The rest of the matrix is filled with orange diagonal hatching. A vertical red line is drawn between the first and second columns, and a horizontal red line is drawn between the first and second rows, intersecting at the top-left corner of the hatched region.

- Vectors V span a subspace S
- Learn inner product between V and unknown vector u
- Can learn projection of u onto S
- Cliffords span unital part
- Learn inner product between Cliffords and \mathcal{E}
- Learn projection of \mathcal{E} onto unital subspace

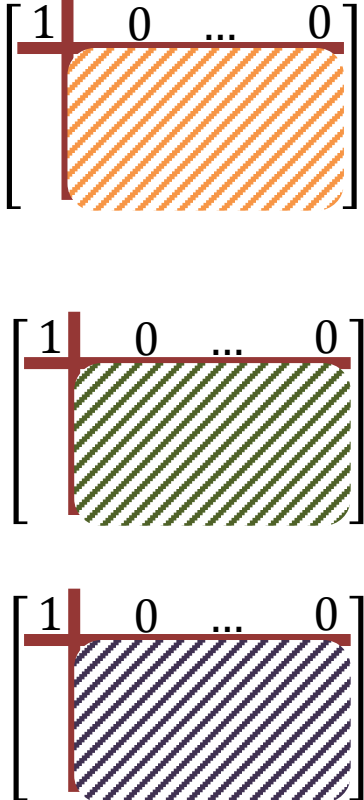
2. Dealing with Errors



2. Dealing with Errors



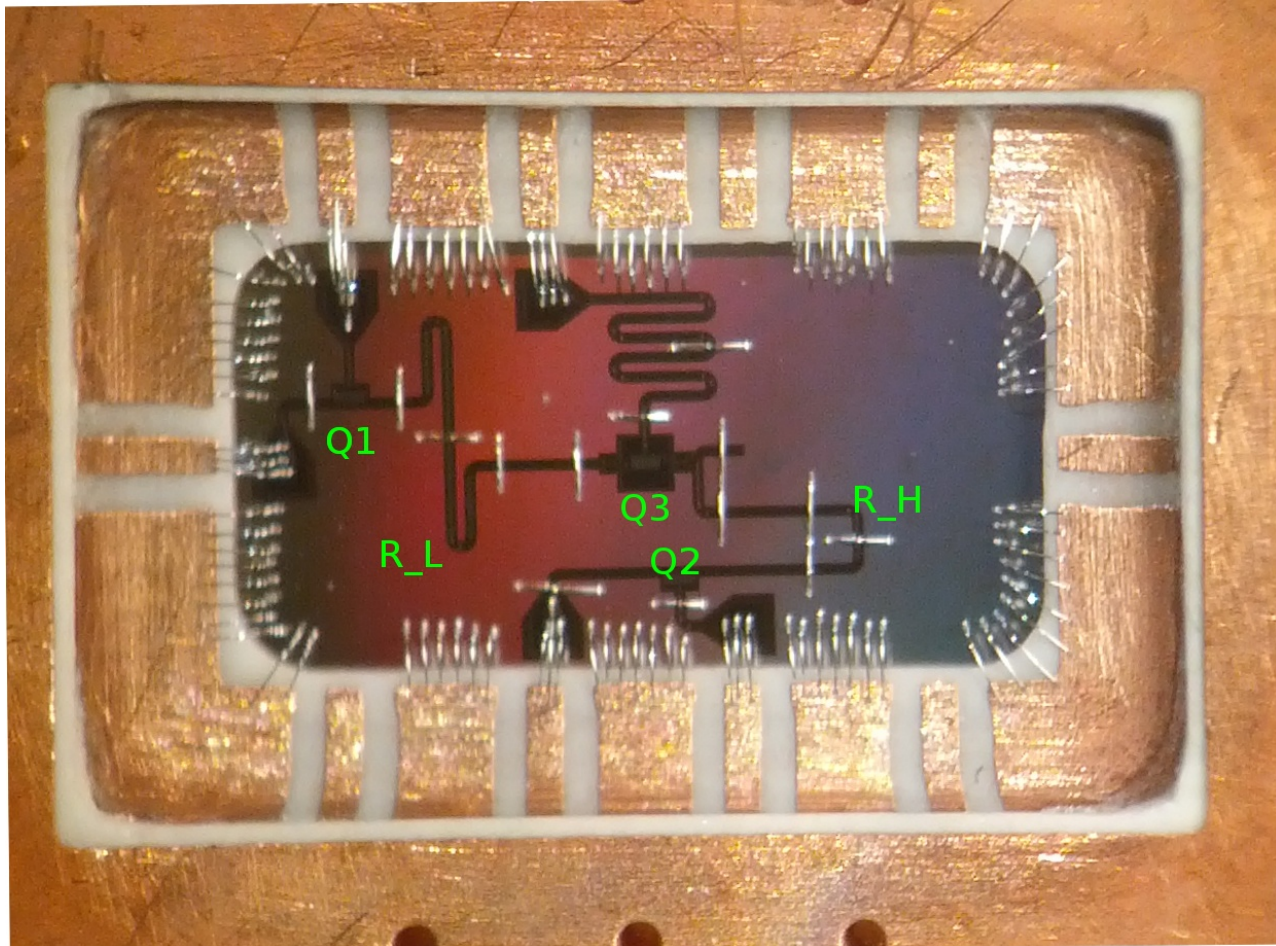
2. Dealing with Errors

$$\begin{array}{l} \text{almost complete characterization of } \Lambda_C \\ + \\ \text{almost complete characterization of } \Lambda_C \circ \mathcal{E} \\ = \\ \text{almost complete characterization of } \mathcal{E} \end{array}$$


The diagram illustrates the derivation of an almost complete characterization of \mathcal{E} from two other characterizations. It consists of three augmented matrices stacked vertically, connected by a plus sign and an equals sign. Each matrix is enclosed in large square brackets. The top row of each matrix contains the elements 1 , 0 , an ellipsis \dots , and 0 . The remaining rows of each matrix are filled with diagonal hatching. The first matrix has orange hatching, the second has green hatching, and the third has blue hatching.

All without the systematic errors of previous procedures!

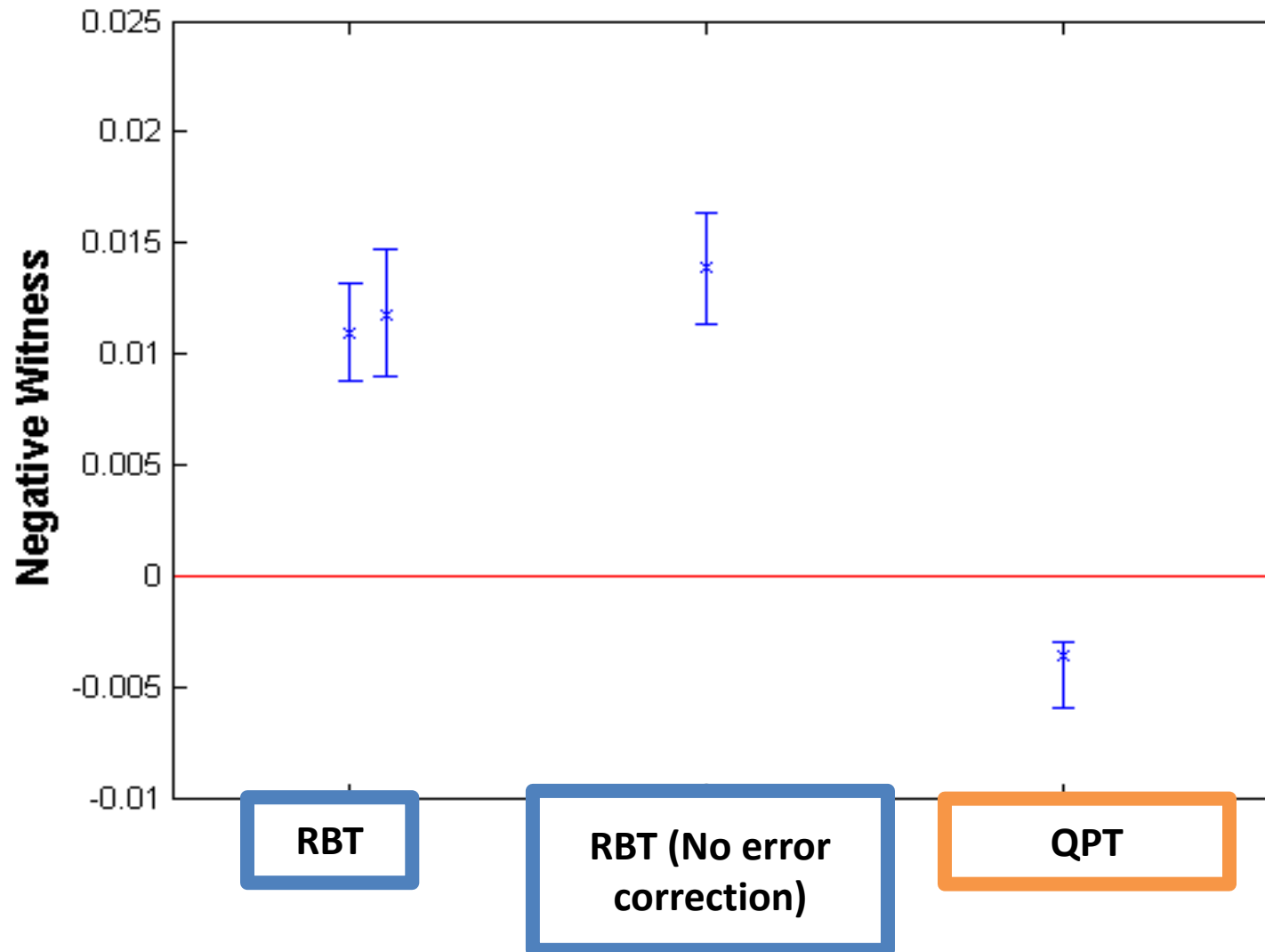
Experimental Implementation



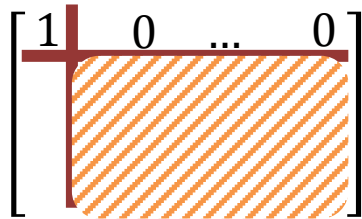
Negative Witness Test [Moroder et al. '13]

- To be a valid quantum process, must be trace preserving and completely positive
- Complete positivity = in Choi representation, all eigenvalues must be positive
- Negative witness test:
 - Look at value of smallest eigenvalues of reconstructed map in Choi representation.
 - If negative, BAD!

Negative Witness Test for Hadamard



Efficient Fidelity Estimate

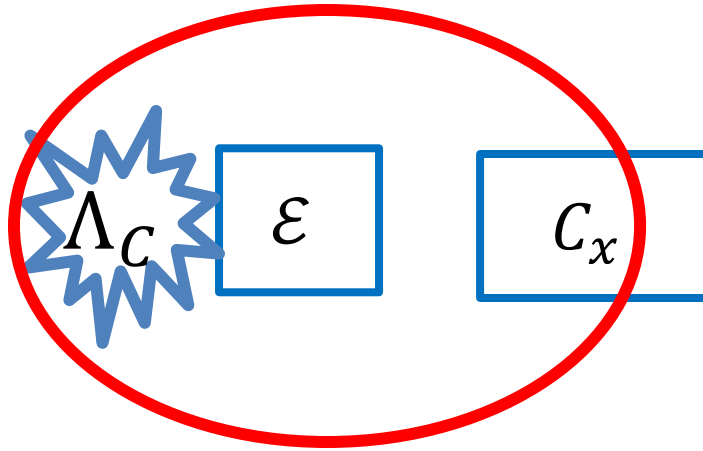


Requires an exponential number of measurement settings with different C_x

Instead, only want to check that your operations are good enough.

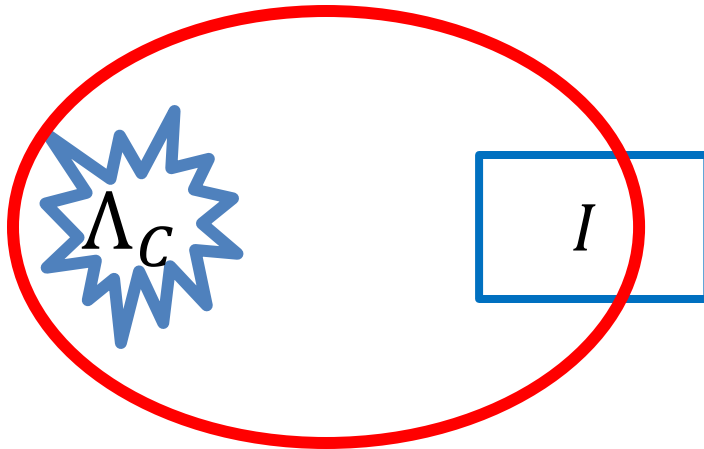
Want to check implementation of Clifford Gates and T gates
= universal gate set

Efficient Fidelity Estimate



Average fidelity to any unitary \mathcal{U} of

- $O(\log n)$ T gates
 - $O(\text{poly } n)$ Cliffords
- only need to repeat for $O(\text{poly } n)$ different C_x .



If Λ_C is close to Identity, can closely bound the average fidelity of \mathcal{E} to \mathcal{U} .

Can test a universal gate set!


Conclusions and Open Questions

- Can robustly measure unital part of any quantum process
- Can efficiently and robustly test fidelity of universal quantum gate set operations.
- Experimentally implemented with superconducting qubit system at BBN

- What about the non-unital part?
- Can we extract other information efficiently and robustly (compressed sensing?)
- How does RB compare to Gate Set Tomography methods?

Efficient Fidelity Estimate

$$\text{Average Fidelity } (\mathcal{E}, U) \sim \text{tr} \left[\begin{bmatrix} \vdots & \boxed{\mathcal{E}} & \vdots \\ \dots & & \dots \end{bmatrix} \begin{bmatrix} \vdots & \boxed{U} & \vdots \\ \dots & & \dots \end{bmatrix} \right]$$

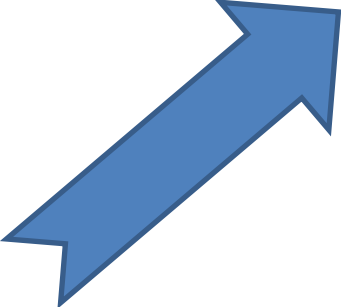


$$\sum_x a_x \begin{bmatrix} \vdots & \boxed{C_x} & \vdots \\ \dots & & \dots \end{bmatrix}$$

Unitaries composed of Cliffords and $O(\log n)$ T gates can be written as a linear combination of $O(\text{poly } n)$ Cliffords.

Only need to measure $O(\text{poly } n)$ traces, each of which can be done efficiently.

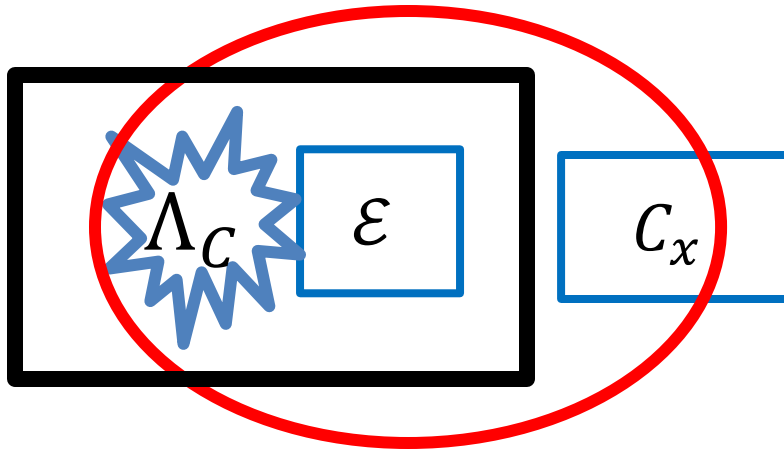
Efficient Fidelity Estimate

$$\text{Average Fidelity } (\mathcal{E}, U) \sim \text{tr} \left[\begin{bmatrix} \Lambda_C \circ \mathcal{E} & \vdots \\ \dots & \dots \end{bmatrix} \begin{bmatrix} \vdots & U & \vdots \\ \dots & \dots & \dots \end{bmatrix} \right]$$


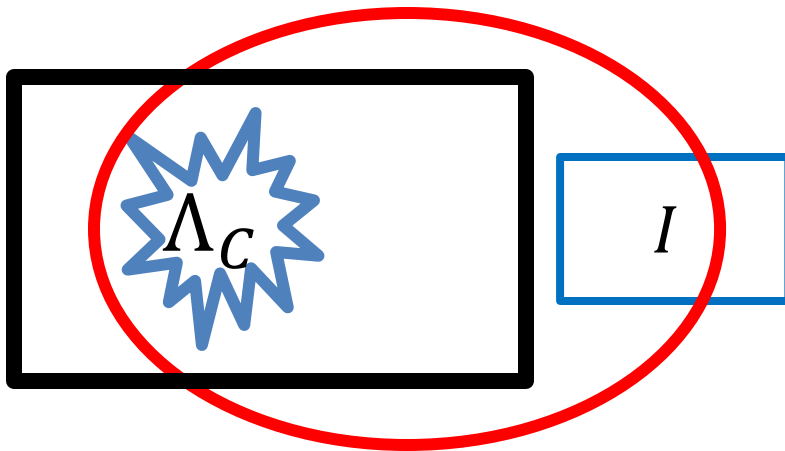
$$\sum_x a_x \begin{bmatrix} \vdots & C_x & \vdots \\ \dots & \dots & \dots \end{bmatrix}$$

Since we haven't characterized Λ_C , we can't get rid of its effect. However, we can measure its average fidelity to the identity, and if it is close to the identity, we can bound its effect

Efficient Fidelity Estimate



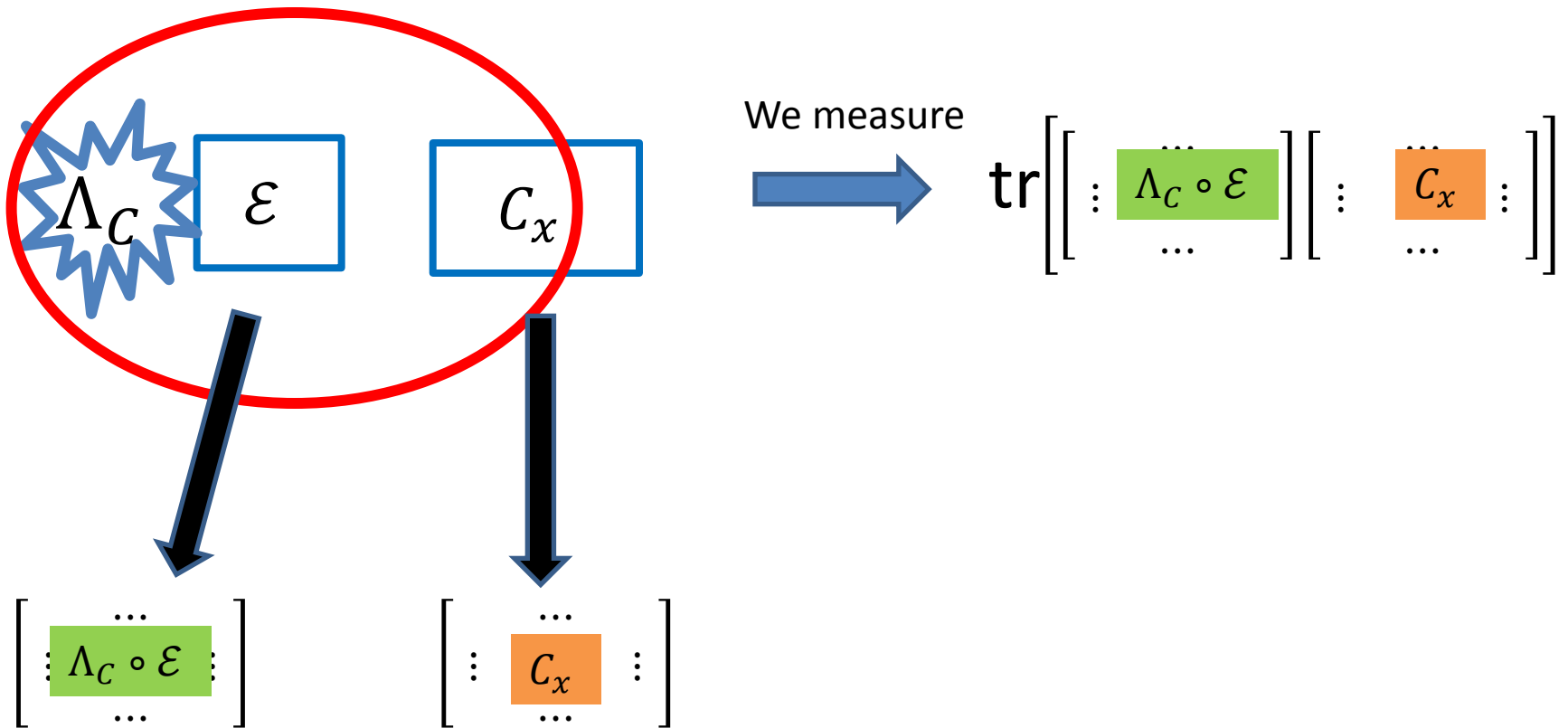
To get average fidelity to any unitary \mathcal{U} of $O(\log n)$ T gates and $O(\text{poly } n)$ Cliffords, only need to repeat for $O(\text{poly } n)$ overlaps C_x .



If Λ_C is close to Identity, can closely bound the average fidelity of \mathcal{E} to \mathcal{U} .

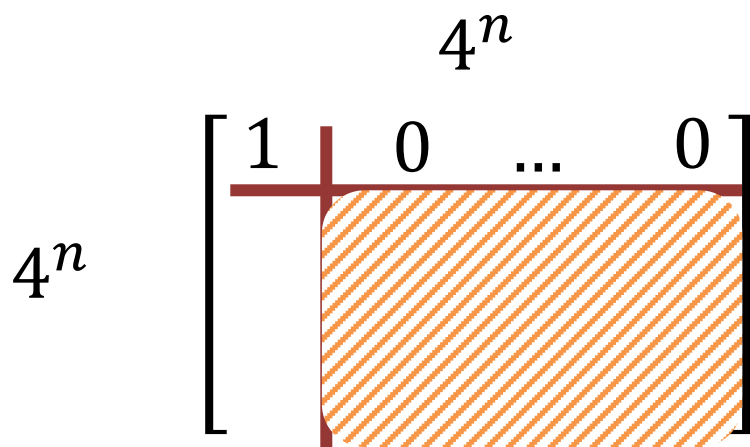
Can test a universal gate set!

What do we measure?



What can we measure?

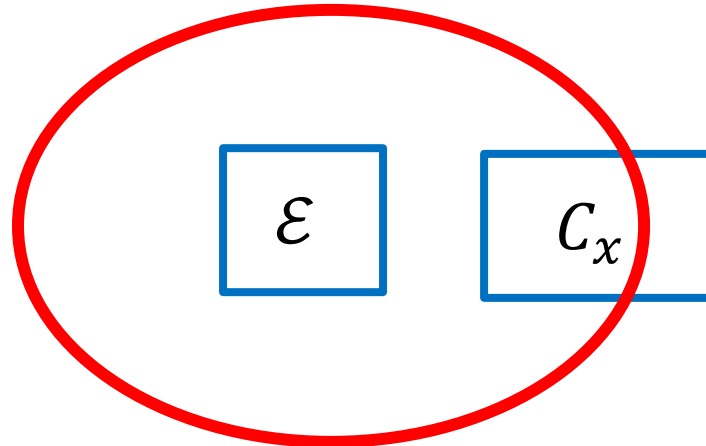
CPTP map: $16^n - 4^n$ parameters for n qubit map



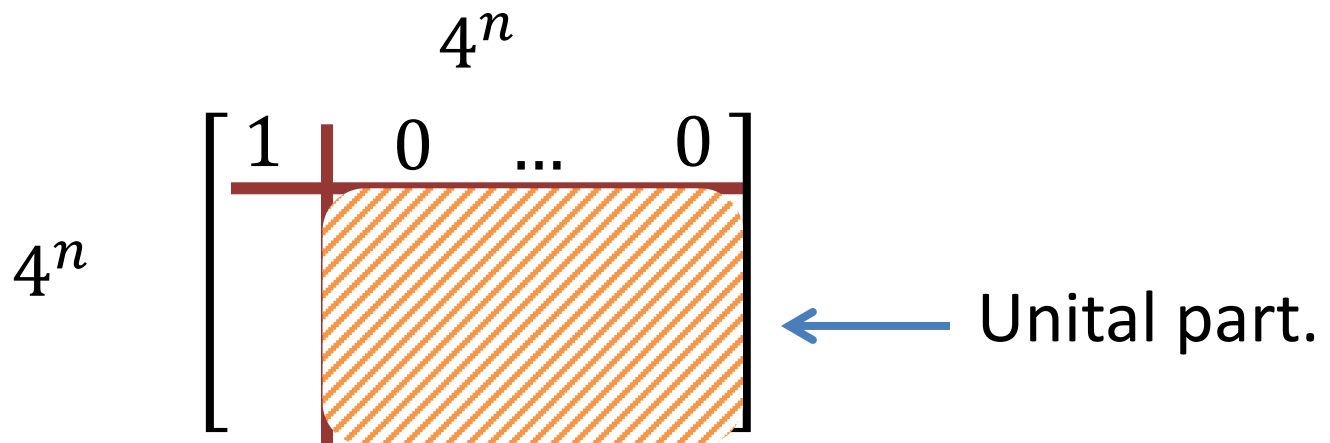
Choose many different C_x 's and measure trace. By measuring enough traces can learn unital part

We learn: $16^n - 2 * 4^n + 1$ parameters

What do we characterize?

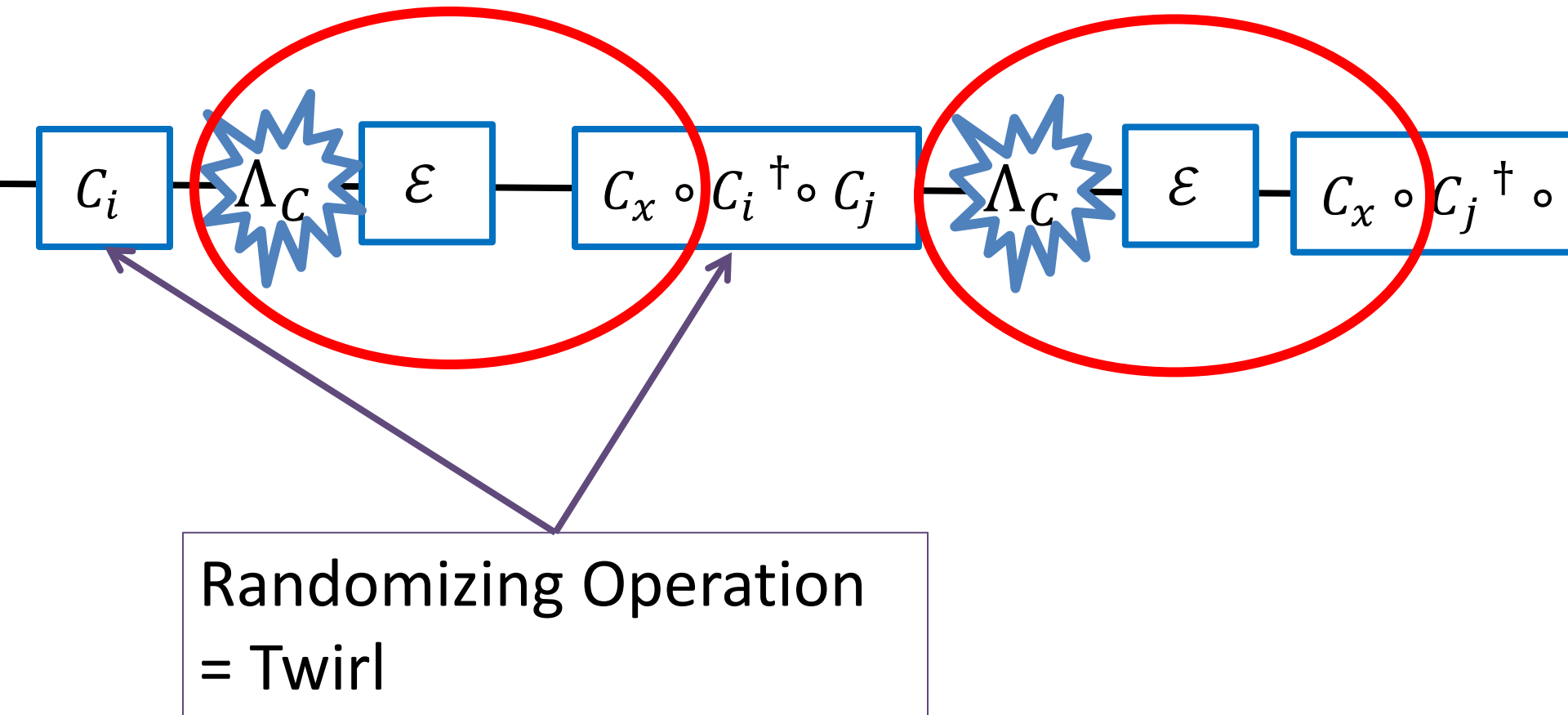


Need to repeat
for 16^n
different C_x



(Pauli-Liouville Representation)

2. Dealing with Errors



Can we do better with Randomized Benchmarking?

- Can we robustly characterize many parameters of any operation?

Can characterize almost all parameters of any quantum map

We show Cliffords span unital part of quantum maps. By learning average fidelity of \mathcal{E} to many C_x 's, can learn projection of \mathcal{E} into unital subspace.

- What information can we obtain robustly *and* efficiently?

Can test performance of a universal gate set.